

SLAS154B - DECEMBER 2002 - REVISED MAY 2003

16-BIT, 1.25 MSPS, UNIPOLAR DIFFERENTIAL INPUT, MICRO POWER SAMPLING ANALOG-TO-DIGITAL CONVERTER WITH PARALLEL INTERFACE AND REFERENCE

FEATURES

- 1.25-MHz Sample Rate
- 16-Bit NMC Ensured Over Temperature
- Zero Latency
- Unipolar Differential Input Range: V_{ref} to -V_{ref}
- Onboard Reference
- Onboard Reference Buffer
- High-Speed Parallel Interface
- Power Dissipation: 155 mW at 1.25 MHz Typ
- Wide Digital Supply
- 8-/16-Bit Bus Transfer
- 48-Pin TQFP Package

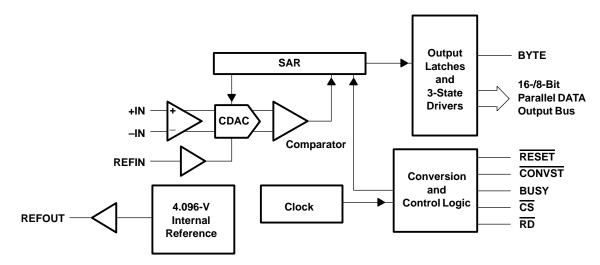
APPLICATIONS

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communication

DESCRIPTION

The ADS8402 is a 16-bit, 1.25 MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8402 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles.

The ADS8402 has a unipolar differential input. It is available in a 48-lead TQFP package and is characterized over the industrial –40°C to 85°C temperature range.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

SLAS154B - DECEMBER 2002 - REVISED MAY 2003



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLU- TION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPER- ATURE RANGE	ORDERING INFORMATION	TRANS- PORT MEDIA QUANTITY			
AD004001	10	00		45	48 Pin	48 Pin	555	250	–40°C to	ADS8402IPFBT	Tape and reel 250
ADS8402I	±6	-2~+3	15	TQFP PFB		85°C	ADS8402IPFBR	Tape and reel 1000			
A D 00 400 I D	10.5	4 . 0	40	48 Pin	DED	–40°C to	ADS8402IBPFBT	Tape and reel 250			
ADS8402IB	1402IB ±3.5		l PFB	85°C	ADS8402IBPFBR	Tape and reel 1000					

NOTE: For the most current specifications and package information, refer to our website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1)

			UNIT			
+IN to AGND			+VA + 0.1 V			
Voltage	-IN to AGND		+VA + 0.1 V			
	+VA to AGND		-0.3 V to 7 V			
Voltage range	+VBD to BDGN	+VBD to BDGND				
	+VA to +VBD	-0.3 V to 2.5 V				
Digital input voltag	ge to BDGND	-0.3 V to +VBD + 0.3 V				
Digital output volt	-0.3 V to +VBD + 0.3 V					
Operating free-air temperature range, T _A			-40°C to 85°C			
Storage temperat	ure range, T _{Stg}		–65°C to 150°C			
Junction tempera	ture (T _J max)		150°C			
TOED 1	Powerdissipation	on	(T _J Max – T _A)/θ _{JA}			
TQFP package θ _{JA} thermal imp		edance	86°C/W			
Lead temperature, soldering		Vapor phase (60 sec)	215°C			
		Infrared (15 sec)	220°C			

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



SPECIFICATIONS

 $T_A = -40^{\circ}\text{C}$ to 85°C , +VA = 5 V, +VBD = 3 V or 5 V, V_{ref} = 4.096 V, f_{SAMPLE} = 1.25 MHz (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Analog Input		•	,				
Full-scale input voltage (see Note 1)	+ININ	-V _{ref}		V _{ref}	V		
Absolute input voltage		+IN	-0.2		V _{ref} + 0.2	.,	
		-IN	-0.2		V _{ref} + 0.2	V	
Common-mode input range	ADS8402I		$(V_{ref}/2) - 0.2$	V _{ref} /2	$(V_{ref}/2) + 0.2$	V	
Input capacitance	•			25		pF	
Input leakage current				0.5		nA	
System Performance							
Resolution				16		Bits	
	ADS8402I		15				
No missing codes	ADS8402IB		16			Bits	
	ADS8402I		-6	±2.5	6		
Integral linearity (see Notes 2 and 3)	ADS8402IB		-3.5	±2	3.5	LSB	
	ADS8402I		-2	±1	3	LSB	
Differentiallinearity	ADS8402IB		-1	±0.75	2		
O"	ADS8402I		-3	±1	3	mV	
Offset error (see Note 4)	ADS8402IB		-1.5	±0.5	1.5	mV	
0: () () ()	ADS8402I		-0.15		0.15	0/50	
Gain error (see Notes 4 and 5)	ADS8402IB		-0.098		0.098	%FS	
O		At dc (±0.2 V around V _{ref} /2)		80		dB	
Common-mode rejection ratio		$+ININ = 1 V_{pp}$ at 1 MHz		80			
Noise				60		μV RMS	
DC Power supply rejection ratio		At 7FFFh output code, +VA = 4.75 V to 5.25 V, Vref = 4.096 V, See Note 4		1		LSB	
SamplingDynamics							
Conversion time					610	ns	
Acquisition time			150			ns	
Throughputrate					1.25	MHz	
Aperture delay				2		ns	
Aperture jitter				25		ps	
Step response				100		ns	
Overvoltage recovery				100		ns	

⁽¹⁾ Ideal input span, does not include gain or offset error.

⁽²⁾ LSB means least significant bit(3) This is endpoint INL, not best fit

⁽⁴⁾ Measured relative to an ideal full-scale input (+IN - -IN) of 8.192 V

⁽⁵⁾ This specification does not include the internal reference voltage error and drift.



SPECIFICATIONS (CONTINUED)

 $T_A = -40$ °C to 85°C, +VA = +5 V, +VBD = 3 V or 5 V, $V_{ref} = 4.096$ V, $f_{SAMPLE} = 1.25$ MHz (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DynamicCharacterist	ics	·				
Total harmonic distortion	on (THD) (see Note 1)	$V_{IN} = 8 V_{pp}$ at 100 kHz		-95		dB
Signal-to-noise ratio (S	NR)	V _{IN} = 8 V _{pp} at 100 kHz		90		dB
Signal-to-noise + distor	tion (SINAD)	V _{IN} = 8 V _{pp} at 100 kHz		88		dB
Spurious free dynamic	range (SFDR)	$V_{IN} = 8 V_{pp}$ at 100 kHz		95		dB
-3dB Small signal band	dwidth			5		MHz
External Voltage Refe	rence Input					
Reference voltage at R			2.5	4.096	4.2	V
Reference resistance (500		kΩ
Internal Reference O	utput		· L			
Internal reference start		From 95% (+VA), with 1 μF storage capacity			120	ms
V _{ref} range		IOUT = 0	4.065	4.096	4.13	V
Source Current		Static load			10	μΑ
Line Regulation		+VA = 4.75 ~ 5.25 V		0.6		mV
Drift		IOUT = 0		36		PPM/C
Digital Input/Output		·	•			
Logicfamily				CMO S		
	VIH	I _{IH} = 5 μA	+VBD-1		+VBD + 0.3	
	V _{IL}	I _I L = 5 μA	-0.3		0.8	
Logic level	VOH	I _{OH} = 2 TTL loads	+VBD - 0.6		+VBD	V
	V _{OL}	I _{OL} = 2 TTL loads	0		0.4	
Dataformat			Co	2's omplemen	nt	
Power Supply Require	ements	·				
	+VBD (see Notes 3 and 4)		2.95	3.3	5.25	V
Power supply voltage	+VA (see Note 4)		4.75	5	5.25	V
+VA Supply current (see Note 5)		f _S = 1.25 MHz		31	34	mA
Power dissipation (see Note 5)		f _S = 1.25 MHz		155		mW
Temperature Range		'	1			
Operatingfree-air			-40		85	°C
1) 0 -11		1	•			

⁽¹⁾ Calculated on the first nine harmonics of the input frequency
(2) Can vary ±20%
(3) The difference between +VA and +VBD should not be less than 2.3 V, i.e., if +VA is 5.25 V, +VBD should be minimum of 2.95 V.
(4) +VBD ≥ +VA − 2.3 V

⁽⁵⁾ This includes only VA+ current. +VBD current is typically 1 mA with 5 pF load capacitance on output pins.



TIMING CHARACTERISTICS

All specifications typical at -40° C to 85° C, +VA = +VBD = 5 V (see Notes 1, 2, and 3)

PARAMETER	MIN	TYP	MAX	UNIT
Conversion time		600	610	ns
Acquisition time	150			ns
CONVST low to conversion started (BUSY high)			35	ns
Propagation delay time, End of conversion to BUSY low			20	ns
Pulse duration, CONVST low	20			ns
Setup time, CS low to CONVST low	0			ns
Pulse duration, CONVST high	20			ns
CONVST falling edge jitter			10	ps
Pulse duration, BUSY signal low	Min(t _{ACQ})			ns
Pulse duration, BUSY signal high			630	ns
Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40			ns
Delay time, CS low to RD low	0			ns
Setup time, RD high to CS high	0			ns
Pulse duration, RD low time	50			ns
Enable time, RD low (or CS low for read cycle) to data valid			20	ns
Delay time, data hold from RD high	0			ns
Delay time, BYTE rising edge or falling edge to data valid	2		20	ns
RD high	20			ns
Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge	50			ns
Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge	Max(t _{d5})			ns
Setup time, BYTE rising edge to RD falling edge	0			ns
Hold time, BYTE falling edge to RD falling edge	0			ns
Disable time, RD High (CS high for read cycle) to 3-stated data bus			20	ns
Delay time, BUSY low to MSB data valid			0	ns
	Conversion time Acquisition time CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low Setup time, CS low to CONVST low Pulse duration, CONVST high CONVST falling edge jitter Pulse duration, BUSY signal low Pulse duration, BUSY signal low Pulse duration, BUSY signal high Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low Delay time, CS low to RD low Setup time, RD high to CS high Pulse duration, RD low time Enable time, RD low (or CS low for read cycle) to data valid Delay time, data hold from RD high Delay time, BYTE rising edge or falling edge to data valid RD high Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge Betup time, BYTE falling edge to RD falling edge Disable time, RD High (CS high for read cycle) to 3-stated data bus	Acquisition time Acquisition time 150 CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low 20 Setup time, CS low to CONVST low Pulse duration, CONVST high 20 CONVST falling edge jitter Pulse duration, BUSY signal low Pulse duration, BUSY signal high Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low Delay time, CS low to RD low Setup time, RD high to CS high 0 Setup time, RD low (or CS low for read cycle) to data valid Delay time, Adata hold from RD high 0 Delay time, BYTE rising edge or falling edge to data valid 2 RD high Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge Propagation delay time, BUSY falling edge to next RD (or S for read cycle) falling edge 0 Disable time, RD High (CS high for read cycle) to 3-stated data bus	Conversion time 150 Acquisition time 150 CONVST low to conversion started (BUSY high) Propagation delay time, End of conversion to BUSY low Pulse duration, CONVST low 20 Setup time, CS low to CONVST low 0 Pulse duration, CONVST high 20 CONVST falling edge jitter Pulse duration, BUSY signal low Min(tACQ) Pulse duration, BUSY signal low Min(tACQ) Pulse duration, BUSY signal high 40 Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low 0 Setup time, CS low to RD low 0 Setup time, RD high to CS high 0 Pulse duration, RD low time 50 Enable time, RD low (or CS low for read cycle) to data valid 0 Delay time, data hold from RD high 0 Delay time, BYTE rising edge or falling edge to data valid 2 RD high 20 Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge 50 Propagation delay time, BUSY falling edge to RD falling edge 60 Disable time, RD High (CS high for read cycle) to 3-stated data bus	Conversion time 600 610 Acquisition time 150

 ⁽¹⁾ All input signals are specified with t_r = t_f = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V_{IL} + V_{IH})/2.
 (2) See timing diagrams.
 (3) All timings are measured with 20 pF equivalent loads on all data bits and BUSY pins.



TIMING CHARACTERISTICS

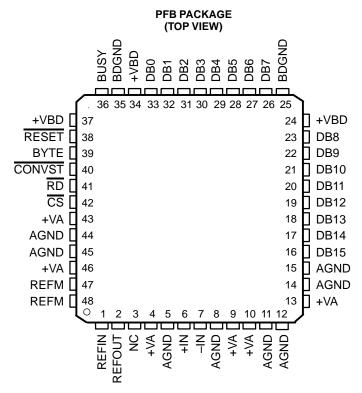
All specifications typical at -40°C to 85°C, +VA = 5 V, +VBD = 3 V (see Notes 1, 2, and 3)

	PARAMETER	MIN	TYP	MAX	UNIT
tCONV	Conversion time		600	610	ns
tACQ	Acquisition time	150			ns
tpd1	CONVST low to conversion started (BUSY high)			40	ns
tpd2	Propagation delay time, end of conversion to BUSY low			20	ns
t _{w1}	Pulse duration, CONVST low	20			ns
t _{su1}	Setup time, CS low to CONVST low	0			ns
t _{w2}	Pulse duration, CONVST high	20			ns
	CONVST falling edge jitter			10	ps
t _{w3}	Pulse duration, BUSY signal low	Min(t _{ACQ})			ns
t _{w4}	Pulse duration, BUSY signal high			630	ns
^t h1	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE or BUS 16/16 input changes) after CONVST low	40			ns
^t d1	Delay time, CS low to RD low	0			ns
t _{su2}	Setup time, RD high to CS high	0			ns
t _{w5}	Pulse duration, RD low	50			ns
ten	Enable time, RD low (or CS low for read cycle) to data valid			30	ns
t _{d2}	Delay time, data hold from RD high	0			ns
t _{d3}	Delay time, BUS16/16 or BYTE rising edge or falling edge to data valid	2		30	ns
t _{w6}	Pulse duration, RD high time	20			ns
th2	Hold time, last RD (or CS for read cycle) rising edge to CONVST falling edge	50			ns
t _{pd4}	Propagation delay time, BUSY falling edge to next RD (or CS for read cycle) falling edge	Max(td5)			ns
t _{su3}	Setup time, BYTE rising edge to RD falling edge	0			ns
t _{h3}	Hold time, BYTE falling edge to RD falling edge	0			ns
tdis	Disable time, RD High (CS high for read cycle) to 3-stated data bus			30	ns
t _{d5}	Delay time, BUSY low to MSB data valid delay time			0	ns

 ⁽¹⁾ All input signals are specified with t_r = t_f = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V_{IL} + V_{IH})/2.
 (2) See timing diagrams.
 (3) All timings are measured with 10 pF equivalent loads on all data bits and BUSY pins.



PIN ASSIGNMENTS



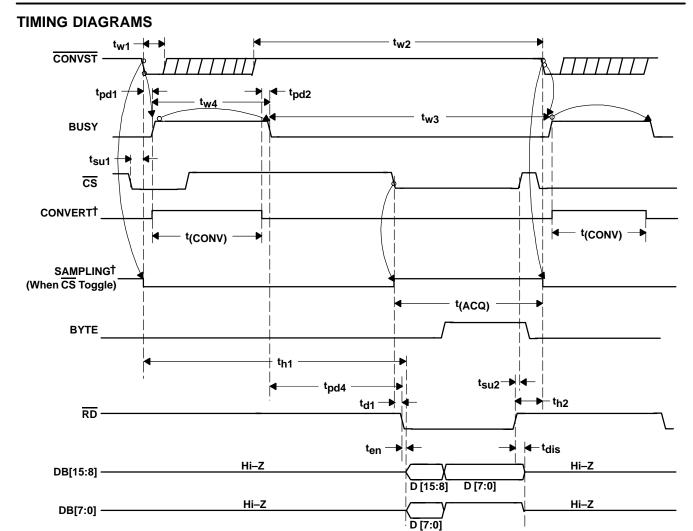
NC - No connection



TERMINAL FUNCTIONS

NAME	NO.	I/O	DESCRIPTION					
AGND	5, 8, 11, 12, 14, 15, 44, 45	-	Analogground	nalogground				
BDGND	25, 35	-	Digital ground for bus interface dig	gital supply				
BUSY	36	0	Status output. High when a conve	ersion is in progress.				
BYTE	39	I	0: No fold back	: Low byte D[7:0] of the 16 most significant bits is folded back to high byte of the 16 most significant				
CONVST	40	I	Convert start					
CS	42	I	Chip select					
			8-B	it Bus	16-Bit Bus			
Data Bus			BYTE = 0	BYTE = 1	BYTE = 0			
DB15	16	0	D15 (MSB)	D7	D15 (MSB)			
DB14	17	0	D14	D6	D14			
DB13	18	0	D13	D5	D13			
DB12	19	0	D12	D4	D12			
DB11	20	0	D11	D3	D11			
DB10	21	0	D10	D2	D10			
DB9	22	0	D9	D1	D9			
DB8	23	0	D8	D0 (LSB)	D8			
DB7	26	0	D7	Allones	D7			
DB6	27	0	D6	Allones	D6			
DB5	28	0	D5	Allones	D5			
DB4	29	0	D4	Allones	D4			
DB3	30	0	D3	Allones	D3			
DB2	31	0	D2	Allones	D2			
DB1	32	0	D1	Allones	D1			
DB0	33	0	D0 (LSB)	Allones	D0 (LSB)			
-IN	7	I	Inverting input channel					
+IN	6	ı	Non inverting input channel					
NC	3	-	No connection					
REFIN	1	I	Reference input					
REFM	47, 48	I	Reference ground					
REFOUT	2	0	Reference output. Add 1 μF caparis used.	Reference output. Add 1 μF capacitor between the REFOUT pin and REFM pin when internal reference				
RESET	38	1		Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independantly of CS.				
RD	41	I	Synchronization pulse for the parallel output.					
+VA	4, 9, 10, 13, 43, 46	-	Analog power supplies, 5-V dc					
+VBD	24, 34, 37	_	Digital power supply for bus	Digital power supply for bus				

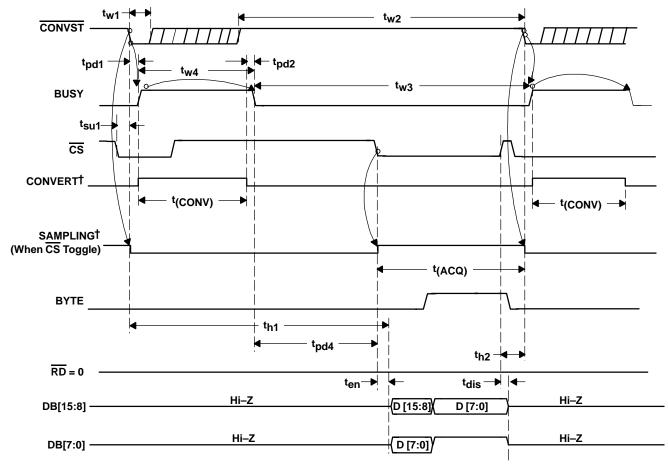




†Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ and $\overline{\text{RD}}$ Toggling

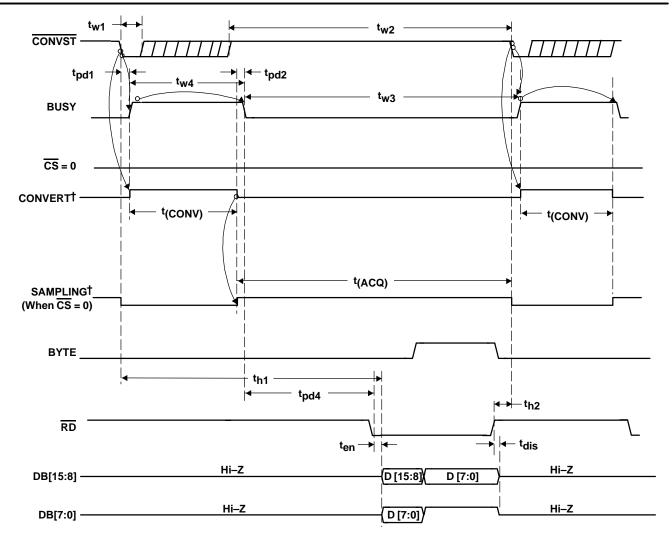




[†]Signal internal to device

Figure 2. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Toggling, $\overline{\text{RD}}$ Tied to BDGND

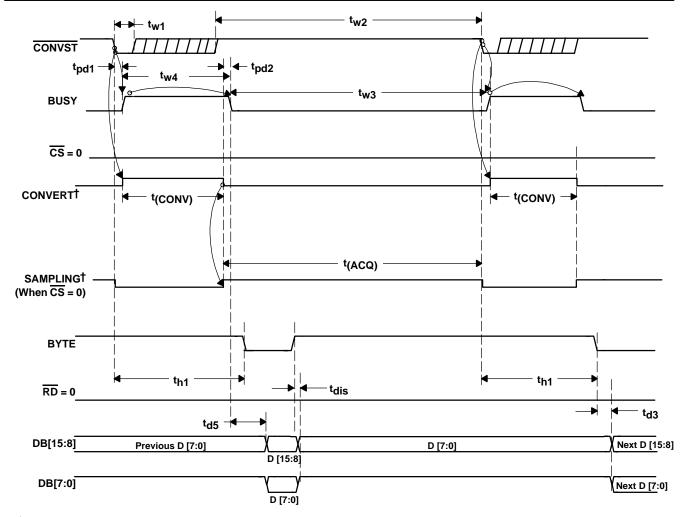




[†]Signal internal to device

Figure 3. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ Tied to BDGND, $\overline{\text{RD}}$ Toggling





†Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With $\overline{\text{CS}}$ and $\overline{\text{RD}}$ Tied to BDGND—Auto Read

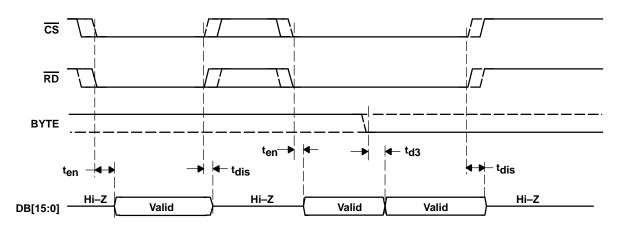
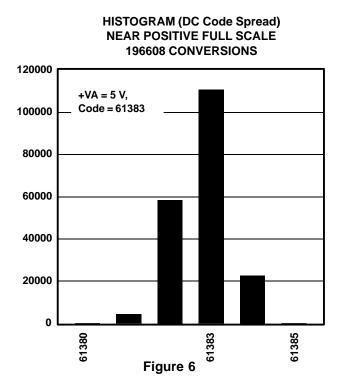
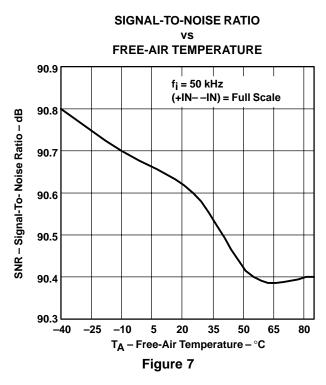


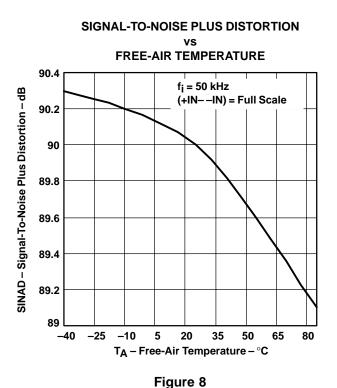
Figure 5. Detailed Timing for Read Cycles

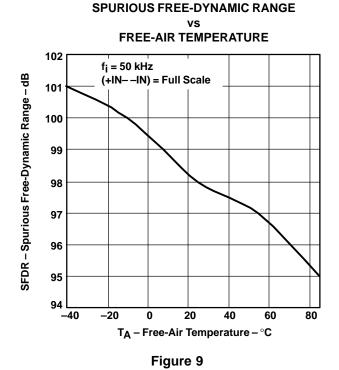


TYPICAL CHARACTERISTICS†



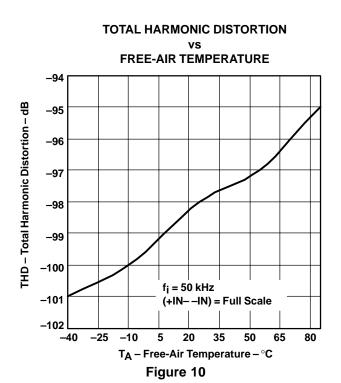


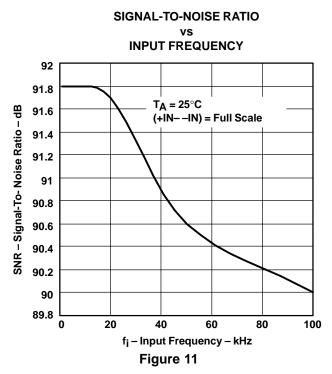


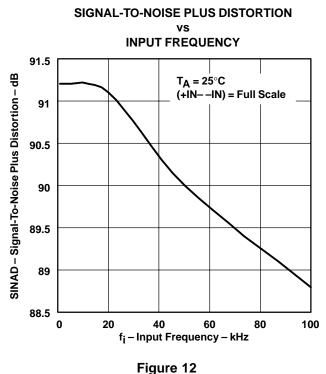


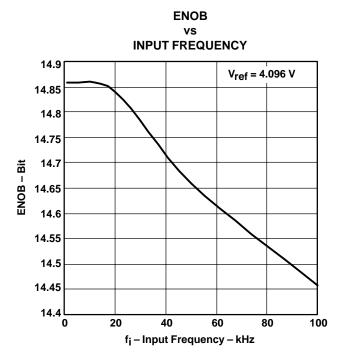
[†] At –40°C to 85°C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and f_{sample} = 1.25 MHz (unless otherwise noted)











e 12 Figure 13

 $^{\ \, ^{\}dagger} \text{At} - 40^{\circ}\text{C to } 85^{\circ}\text{C}, + \text{VA} = 5 \text{ V}, + \text{VBD} = 5 \text{ V}, \\ \text{REFIN} = 4.096 \text{ V (internal reference used)} \\ \text{and } \\ \text{f}_{\text{sample}} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise$

TOTAL HARMONIC DISTORTION



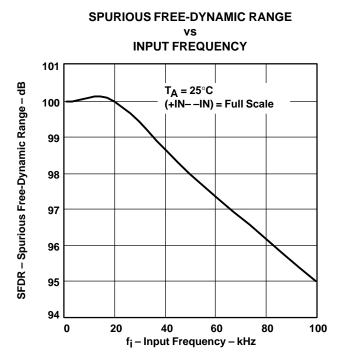
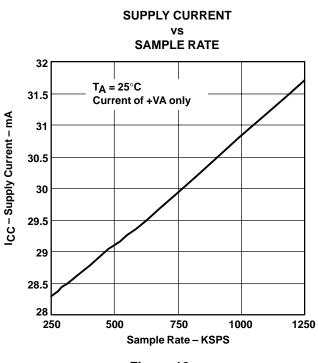


Figure 14

VS INPUT FREQUENCY -94 TA = 25°C (+IN--IN) = Full Scale -96 -97 -99 -100 -101 0 20 40 60 80 100 fi - Input Frequency - kHz

Figure 15





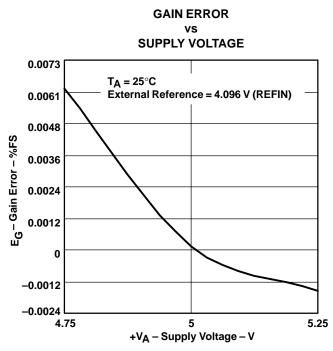
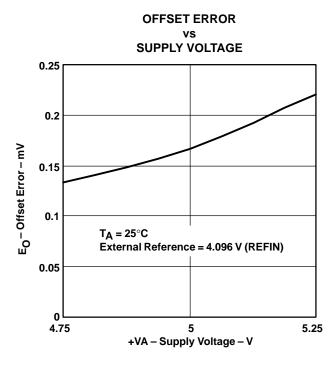


Figure 17



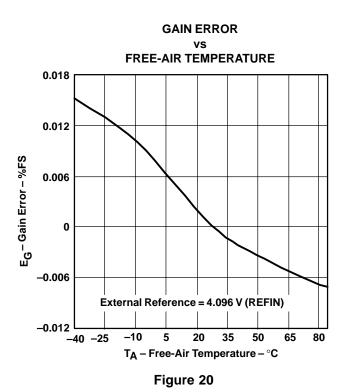


FREE-AIR TEMPERATURE 4.098 - Internal Reference Voltage - V 4.096 4.094 4.092 Vref 4.090 4.088 -25 5 20 35 50 65 80 -40 -10 T_A – Free-Air Temperature – °C

INTERNAL REFERENCE VOLTAGE

Figure 18

Figure 19



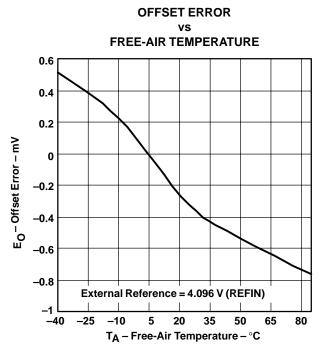


Figure 21

 $[\]dagger$ At -40° C to 85° C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and $f_{sample} = 1.25$ MHz (unless otherwise noted)



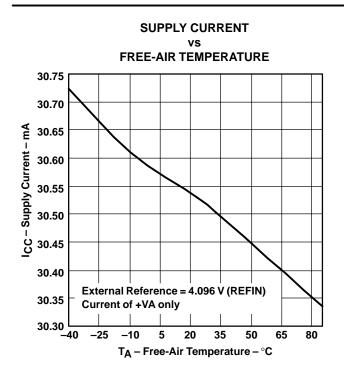


Figure 22

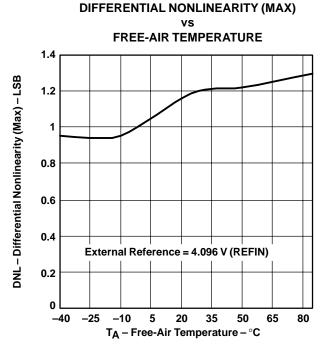


Figure 23

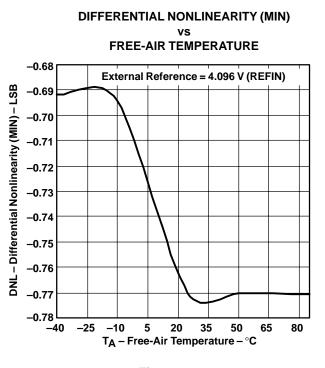


Figure 24

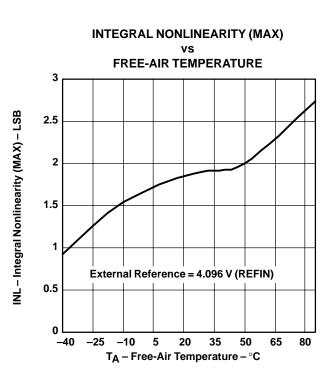
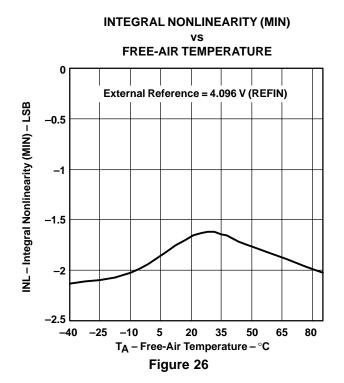
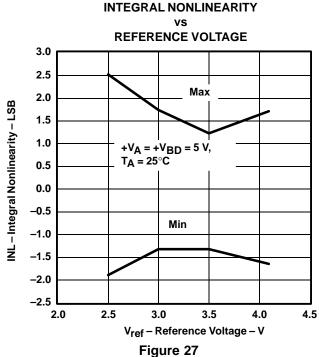


Figure 25

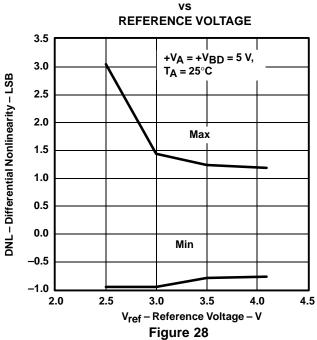
[†] At –40°C to 85°C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and f_{sample} = 1.25 MHz (unless otherwise noted)





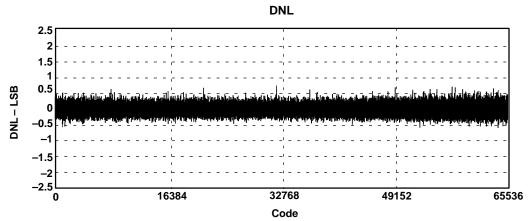


DIFFERENTIAL NONLINEARITY



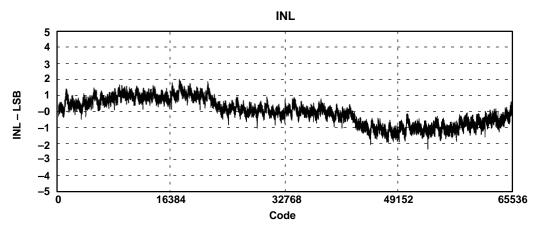
 $^{\ \, ^{\}dagger} \text{At} - 40^{\circ}\text{C to } 85^{\circ}\text{C}, + \text{VA} = 5 \text{ V}, + \text{VBD} = 5 \text{ V}, \\ \text{REFIN} = 4.096 \text{ V (internal reference used)} \\ \text{and } \\ \text{f}_{\text{sample}} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise noted)} \\ \text{The sample} = 1.25 \text{ MHz (unless otherwise$





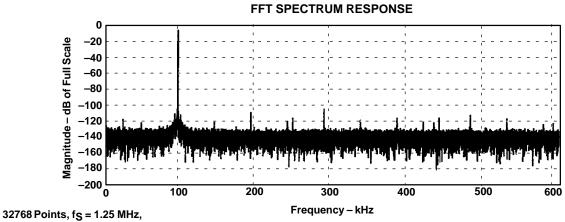
T_A = 25°C, External Reference = 4.096 V (REFIN)

Figure 29



T_A = 25°C, External Reference = 4.096 V (REFIN)

Figure 30



Internal Reference = 4.096 V (REFIN), $T_A = 25^{\circ}C$, $f_i = 100$ kHz, (+IN - -IN) = Full Scale

Figure 31

 $[\]dagger$ At -40° C to 85° C, \pm VA = 5 V, \pm VBD = 5 V, REFIN = 4.096 V (internal reference used) and \dagger sample = 1.25 MHz (unless otherwise noted)



APPLICATION INFORMATION

MICROCONTROLLER INTERFACING

ADS8402 to 8-Bit Microcontroller Interface

Figure 32 shows a parallel interface between the ADS8402 and a typical microcontroller using the 8-bit data bus.

The BUSY signal is used as a falling-edge interrupt to the microcontroller.

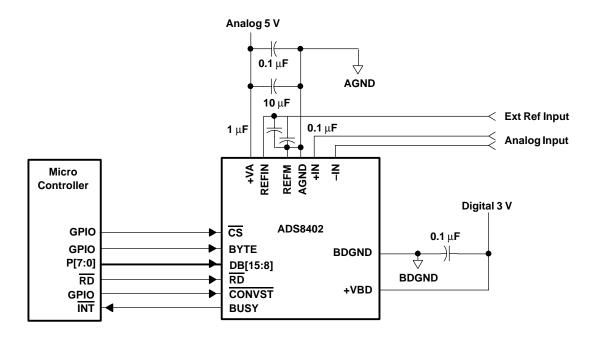


Figure 32. ADS8402 Application Circuitry (using external reference)

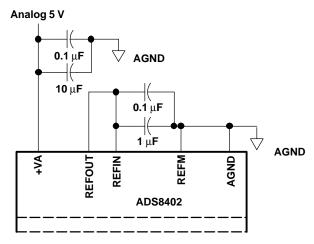


Figure 33. Use Internal Reference



PRINCIPLES OF OPERATION

The ADS8402 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 32 for the application circuit for the ADS8402.

The conversion clock is generated internally. The conversion time of 610 ns is capable of sustaining a 1.25-MHz throughput.

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

REFERENCE

The ADS8402 can operate with an external reference with a range from 2.5 V to 4.2 V. A 4.096-V internal reference is included. When internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with an 0.1 μ F decoupling capacitor and 1 μ F storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 33). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if external reference is used.

ANALOG INPUT

When the converter enters the hold mode, the voltage difference between the +IN and –IN inputs is captured on the internal capacitor array. Both +IN and –IN input has a range of –0.2 V to V_{ref} + 0.2 V. The input span (+IN – (–IN)) is limited to $-V_{ref}$ to V_{ref} .

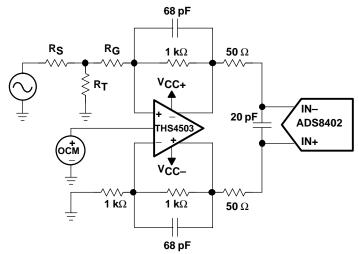
The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8402 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (150 ns) of the device. When the converter goes into the hold mode, the input impedance is greater than 1 $G\Omega$.

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the \pm IN and \pm IN inputs and the span (\pm IN \pm IN) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting time. This may result in offset error, gain error and linearity error which varies with temperature and input voltage.

A typical input circuit using Tl's THS4503 is shown in Figure 34. Input from a single-ended source may be converted into differential signal for ADS8402 as shown in the figure. In case the source itself is differential then THS4503 may be used in differential input and differential output mode.





R_G, R_S, and R_T should be chosen such that R_G + R_S \parallel R_T = 1 k Ω V_{OCM} = 2 V, +V_{CC} = 7 V, and -V_{CC} = -7 V

Figure 34. Using THS4503 With ADS8402

DIGITAL INTERFACE

Timing and Control

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8402 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the $\overline{\text{CONVST}}$ pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the $\overline{\text{CONVST}}$ pin can be brought high), while $\overline{\text{CS}}$ is low. The ADS8402 switches from the sample to the hold mode on the falling edge of the $\overline{\text{CONVST}}$ command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after $\overline{\text{CONVST}}$ goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts with the falling edge of the BUSY signal when \overline{CS} is tied low or starts with the falling edge of \overline{CS} when BUSY is low.

Both \overline{RD} and \overline{CS} can be high during and before a conversion with one exception (\overline{CS} must be low when \overline{CONVST} goes low to initiate a conversion). Both the \overline{RD} and \overline{CS} pins are brought low in order to enable the parallel output bus with the conversion.

Reading Data

The ADS8402 outputs full parallel data in two's complement format as shown in Table 1. The parallel output is active when $\overline{\text{CS}}$ and $\overline{\text{RD}}$ are both low. There is a minimal quiet zone requirement around the falling edge of $\overline{\text{CONVST}}$. This is 100 ns prior to the falling edge of $\overline{\text{CONVST}}$ and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of $\overline{\text{CS}}$ and $\overline{\text{RD}}$ sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the conversion result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.



		-			
DESCRIPTION	ANALOG VALUE	DIGITAL GUITDUT TWOO	OMBI EMENT		
FULL SCALE RANGE	2V _{ref}	DIGITAL OUTPUT TWOS COMPLEMENT			
Least significant bit (LSB)	2V _{ref} /65536	BINARY CODE	HEX CODE		
Full scale	V _{ref}	0111 1111 1111 1111	7FFF		
Midscale	0	0000 0000 0000 0000	0000		
Zero	-\/+	1000 0000 0000 0000	8000		

Table 1. Ideal Input Voltages and Output Codes

The output data is a full 16-bit word (D15-D0) on DB15-DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15–DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15–DB8, then bringing BYTE high. When BYTE is high, the low bits (D7–D0) appears on pins DB15–D8.

These multiword read operations can be done with multiple active RD (toggling) or with RD tied low for simplicity.

DVTE	DATA READ OUT				
BYTE	DB15-DB8	DB7-DB0			
High	D7-D0	All one's			
Low	D15-D8	D7-D0			

RESET

RESET is an asynchronous active low input signal (that works independently of \overline{CS}). Minimum RESET low time is 20 ns. Current conversion will be aborted no later than 50 ns after the converter is in the reset mode. In addition, all output latches are cleared (set to zero's) after RESET. The converter goes back to normal operation mode no later than 20 ns after RESET input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

POWER-ON INITIALIZATION

One RESET pulse followed by three conversion cycles must be given to the converter after powerup to ensure proper operation. The next pulse can be issued once both +VA and +VBD reach 95% of the minimum required value.

LAYOUT

For optimum performance, care should be taken with the physical layout of the ADS8402 circuitry.

As the ADS8402 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8402 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1- μ F bypass capacitor and 1- μ F storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

TEXAS INSTRUMENTS

SLAS154B - DECEMBER 2002 - REVISED MAY 2003

The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.

As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8402 should be clean and well bypassed. A 0.1- μ F ceramic bypass capacitor should be placed as close to the device as possible. See Table 2 for the placement of the capacitor. In addition, a 1- μ F to 10- μ F capacitor is recommended. In some situations, additional bypassing may be required, such as a 100- μ F electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

Table 2. Power Supply Decoupling Capacitor Placement

POWER SUPPLY PLANE	CONVERTED ANALOGOUS	CONVERTED DIGITAL CIDE	
SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE	
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)	
Pins that require no decoupling	12, 14	37	





com 27-Sep-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
ADS8402IBPFBR	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IBPFBRG4	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IBPFBT	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IBPFBTG4	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IPFBR	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IPFBRG4	ACTIVE	TQFP	PFB	48	1000	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR
ADS8402IPFBT	ACTIVE	TQFP	PFB	48	250	Green (RoHS & no Sb/Br)	Call TI	Level-2-260C-1 YEAR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

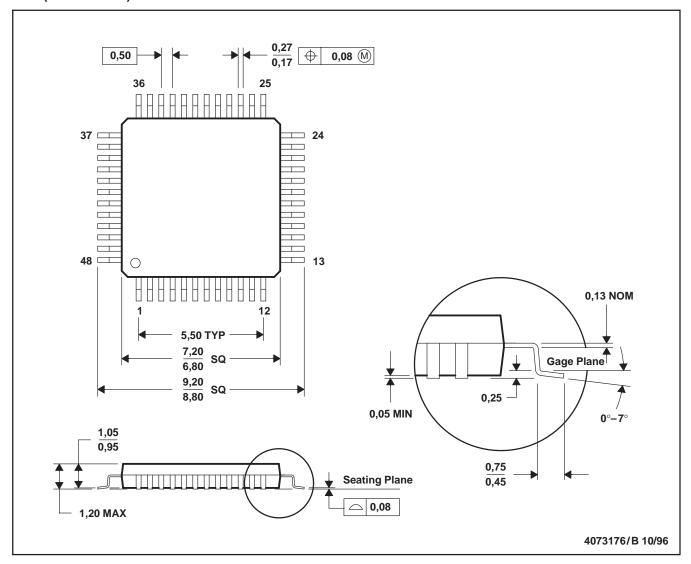
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PFB (S-PQFP-G48)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright © 2005, Texas Instruments Incorporated